Supporting Information

Thermal Degradation Related to Hole Transport Layer and Back Electrode of Flexible Inverted Organic Photovoltaic Module

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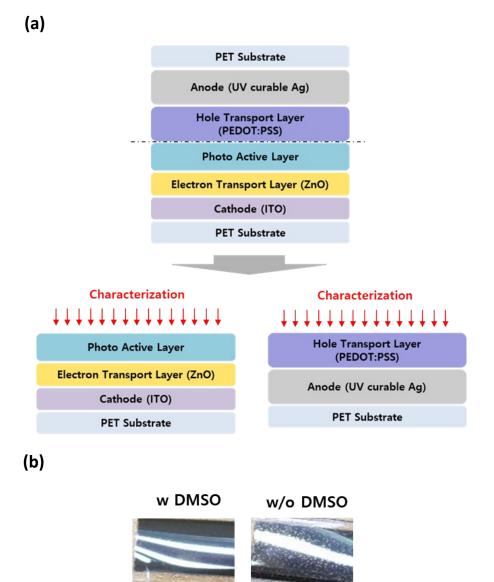


Figure S1. (a) Illustration and (b) photograph showing the method of accessing interlayers of the OPV module by delaminating between the active (upper) and PEDOT:PSS layers with and without DMSO (bottom).

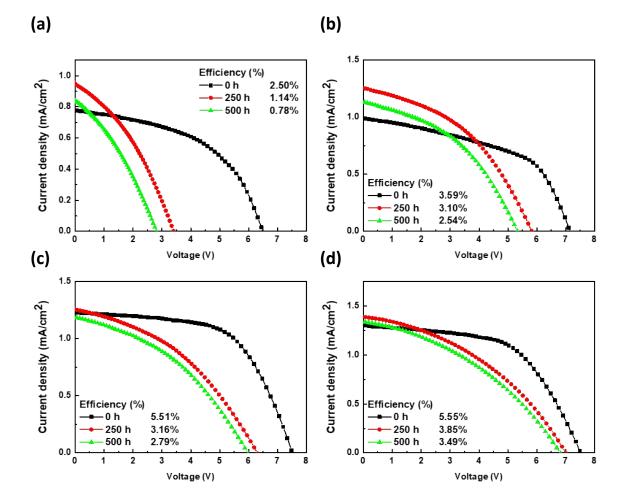


Figure S2. Degradation in J-V characteristics of the OPV devices with different thickness of the PEDOT:PSS HTL as they were thermally aged at 85 °C in the same chamber. Each graph corresponds to the device with (a) 250 nm, (b) 500 nm, (c) 700, and 1400 nm thick PEDOT:PSS HTLs.